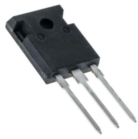

NGTB75N65FL2WG alternative

IGBT Transistors 650V/35A FAST IGBT FSII T

650 V Trench and Fieldstop IGBT

PRODUCT SUMMARY		
V_{CE} (V)	650	
I_C (A)	160 (TC=25℃)	80 (TC=100℃)
VCE（sat） (V)	1.7	
ICM (A)	240	

FEATURES

- Very Low VCEsat
- Low turn-off losses
- High speed switching
- Maximum junction temperature 175°C
- Ultra low gate charge (Q_g)
- Avalanche energy rated (UIS)

APPLICATIONS

- Telecommunications
  - Server and telecom power supplies
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Consumer and computing
  - ATX power supplies
- Industrial
  - Welding
  - Battery chargers
- Renewable energy
  - Solar (PV inverters)
- Switch mode power supplies (SMPS)

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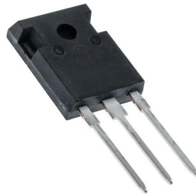
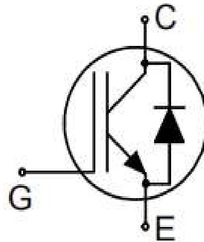




Top View

Package pin definition

- Pin1 G - Gate
- Pin2 C & backside - Collector
- Pin3 E - Emitter

ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C, unless otherwise noted)					
PARAMETER			**SYMBOL**	**LIMIT**	**UNIT**
Collector-Emitter Voltage			V_{CE}	650	V
Gate-Emitter Voltage			V_{GE}	±30	
Continuous Collector Current (T_J = 150 °C)	V_{GE} at 15 V	T_C = 25 °C	I_C	160	A
		T_C = 100 °C		80	
Pulsed Collector Current [a]			I_{CM}	240	
Diode Forward Current [b]			I_F	80	A
Maximum Power Dissipation		T_C = 25 °C	P_D	510	W
		T_C = 100 °C		260	W
Operating Junction and Storage Temperature Range			T_J, T_{stg}	-55 to +175	°C
Short Circuit Withstand Time TC=150℃	VGE= 15V, VCE≤ 400V		tSC	3	μs
Short Circuit Withstand Time TC=100℃	VGE= 15V, VCE≤330V			5	
Soldering Recommendations (Peak Temperature) [c]	for 10 s			260	°C

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature.

b. Current limited by maximum junction temperature.

c. 1.6 mm from case.

NGTB75N65FL2WG alternative

THERMAL RESISTANCE RATINGS				
PARAMETER	**SYMBOL**	**TYP.**	**MAX.**	**UNIT**
Maximum Junction-to-Ambient	R_{thJA}	-	40	°C/W
Maximum Junction-to-Case	R_{thJC}	-	0.5	

SPECIFICATIONS (T_J = 25 °C, unless otherwise noted)						
PARAMETER	**SYMBOL**	**TEST CONDITIONS**	**MIN.**	**TYP.**	**MAX.**	**UNIT**
Static						
Collector-Emitter Breakdown Voltage	BV_{CE}	V_{GE} = 0 V, I_C = 250 μA	650	-	-	V
		V_{GE} = 0 V, I_C = 1 mA	650	-	-	
Gate-Source Threshold Voltage (N)	$V_{GE(th)}$	V_{CE} = V_{GE}, I_D = 250 μA	4	5	6	V
Zero Gate Voltage Collector Current	I_{CES}	V_{CE} = 650 V, V_{GE} = 0 V, T_J = 25 °C	-	1	20	μA
		V_{CE} = 650 V, V_{GE} = 0 V, T_J = 150 °C	-	1000	-	μA
Gate-Emitter Leakage Current	I_{GES}	V_{CE} = 0 V, V_{GS} = ± 2 0 V	-	-	100	nA
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$	V_{GE} = 15 V, I_C = 80 A	-	1.8	2.1	V
Forward Transconductance	g_{fs}	V_{CE} = 20 V, I_C = 80 A	-	40	-	S
Dynamic						
Input Capacitance	C_{ies}	V_{GE} = 0 V, V_{CE} = 25 V, f = 500 KHz	-	8400	-	pF
Output Capacitance	C_{oes}		-	230	-	
Reverse Transfer Capacitance	C_{res}		-	80	-	
Turn-on Energy	E_{on}	V_{CE} = 400 V , V_{GE} = 0 /15V, I_C = 80 A, R_g = 10Ω	-	0.51	-	nJ
Turn-off Energy	E_{off}		-	0.18	-	
Total Gate Charge	Q_g	V_{GE} = 15 V, I_C = 80 A, V_{CE} = 400 V	-	196	-	nC
Gate-Emitter Charge	Q_{ge}		-	21	-	
Gate to Collector Charge	Q_{gc}		-	23	-	
Turn-On Delay Time	$t_{d(on)}$	V_{CE} = 400 V , V_{GE} = 0 /15V, I_C = 80 A, R_g = 10Ω	-	80	-	ns
Rise Time	t_r		-	75	-	
Turn-Off Delay Time	$t_{d(off)}$		-	195	-	
Fall Time	t_f		-	35	-	
Internal emitter inductance measured 5 mm	L_E		-	13	-	nH
Diode Characteristics						
Diode Forward Current	I_F	IGBT symbol showing the integral reverse junction diode	-	-	80	A
Pulsed Diode Forward Current	I_{FM}		-	-	240	
Diode Forward Voltage	V_F	I_F = 80 A	-	1.42	2.0	V
Reverse Recovery Time	t_{rr}	T_J = 25 °C, I_F = 80 A, dI_F/dt = 200 A/μs, V_R = 400 V	-	90	-	ns
Reverse Recovery Charge	Q_{rr}		-	0.15	-	μC
Reverse Recovery Current	I_{RRM}		-	15	-	A

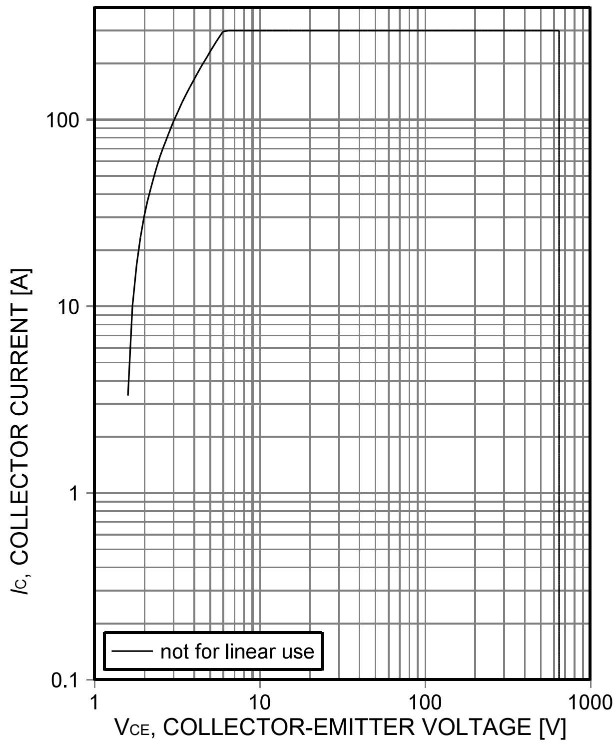


Figure 1.Forward bias safe operating area

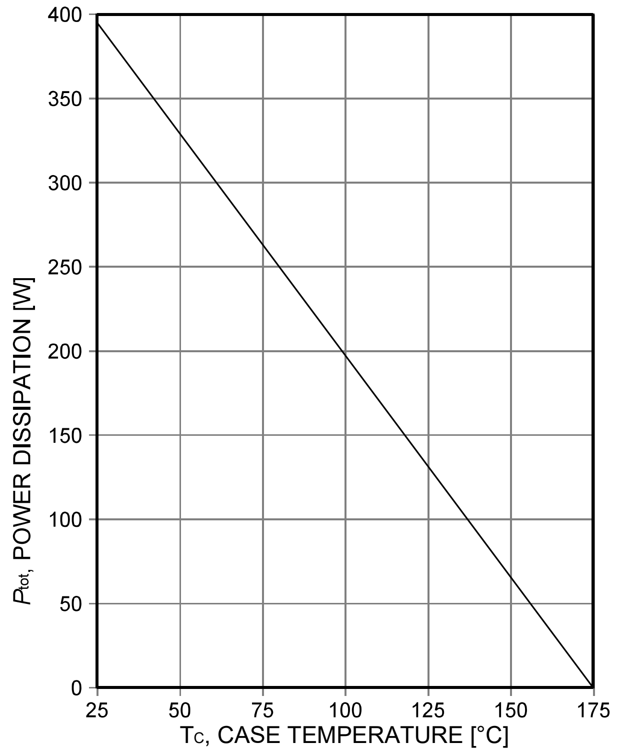


Figure 2.Power dissipation as a function of case

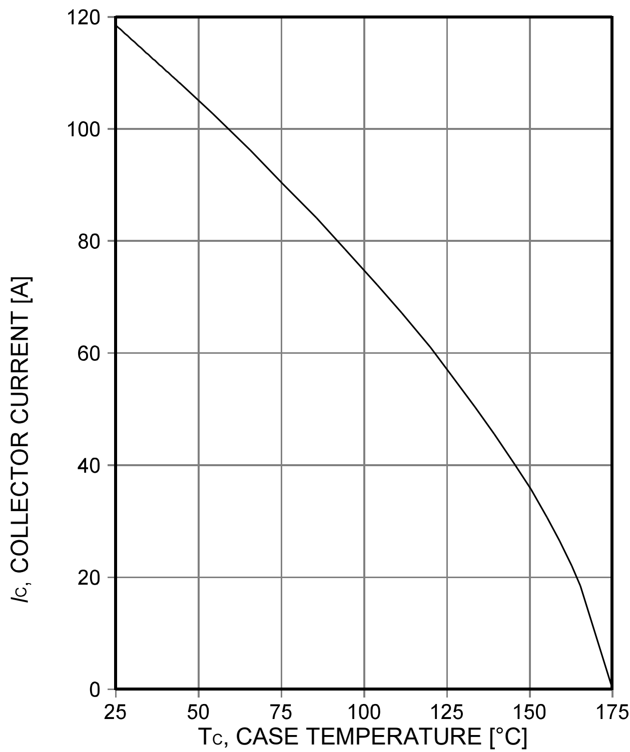


Figure 3.Collector current as a function of case temperature

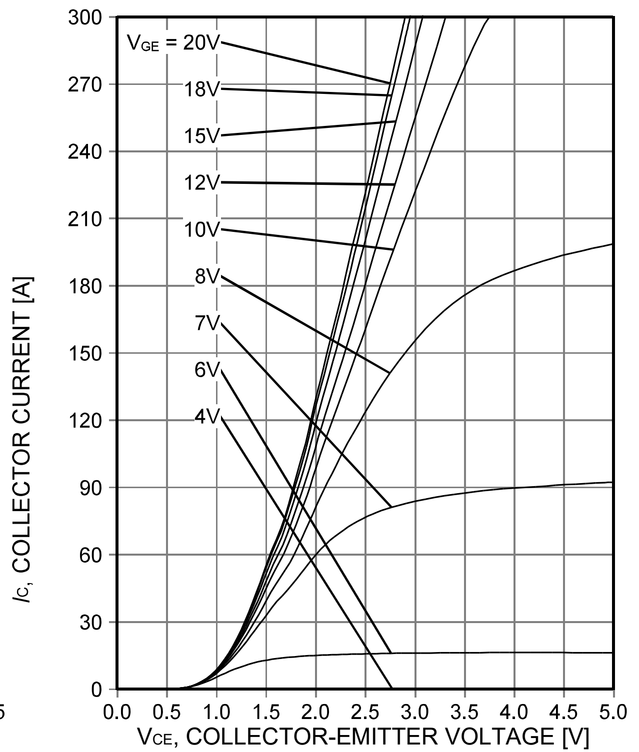


Figure 4.Typical output characteristic

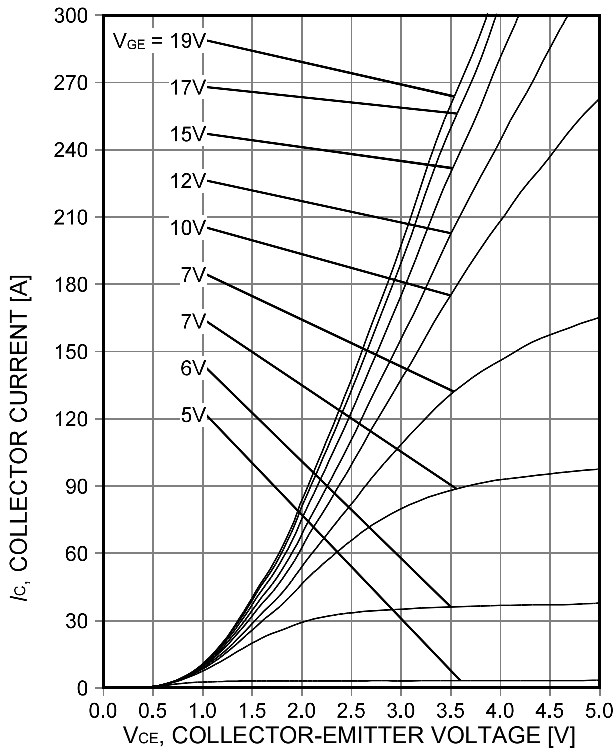


Figure 5.Typical output characteristic

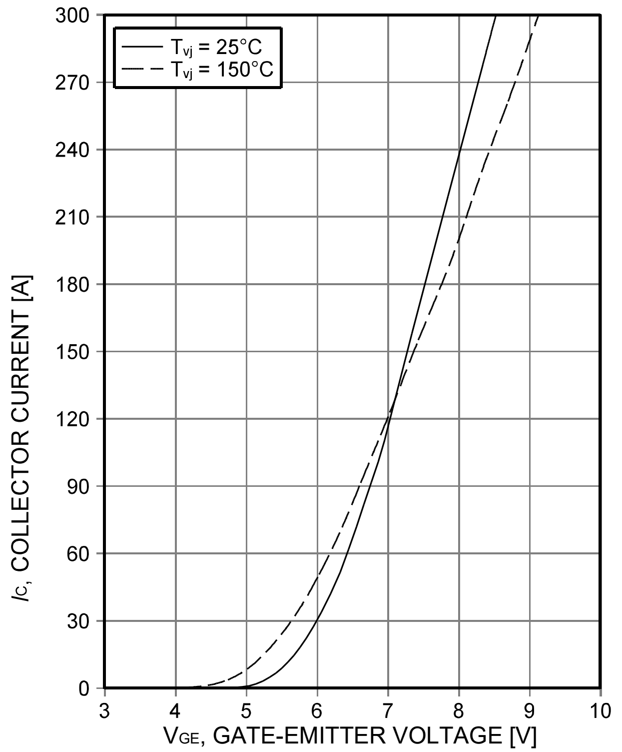


Figure 6.Typical transfer characteristic

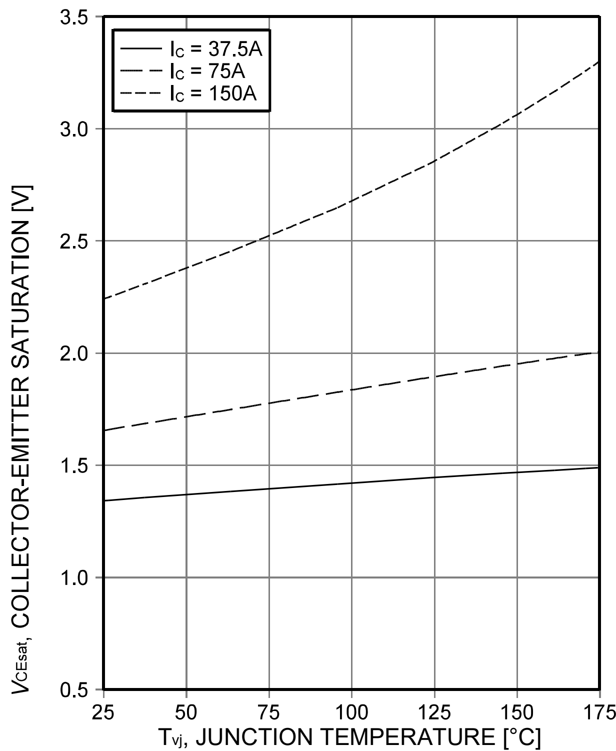


Figure 7. Typical collector-emitter saturation voltage as a function of junction temperature

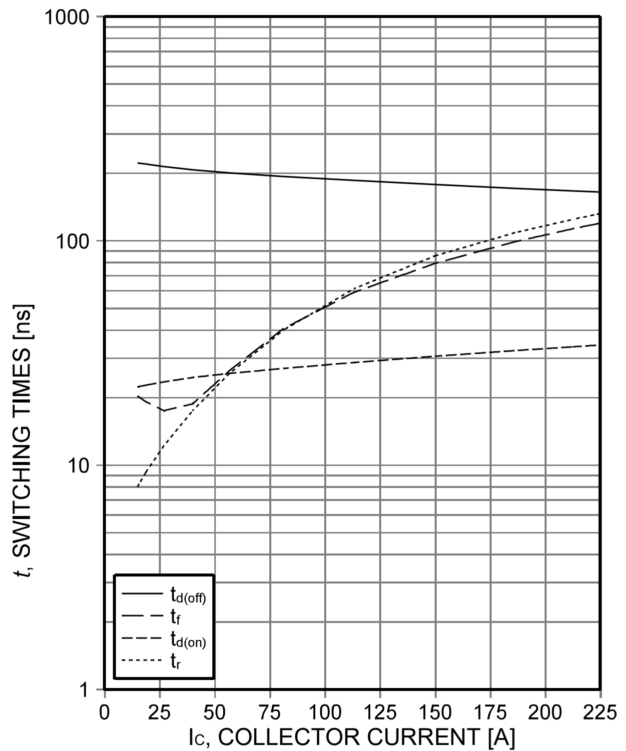


Figure 8.Typical switching times as a function of collector current

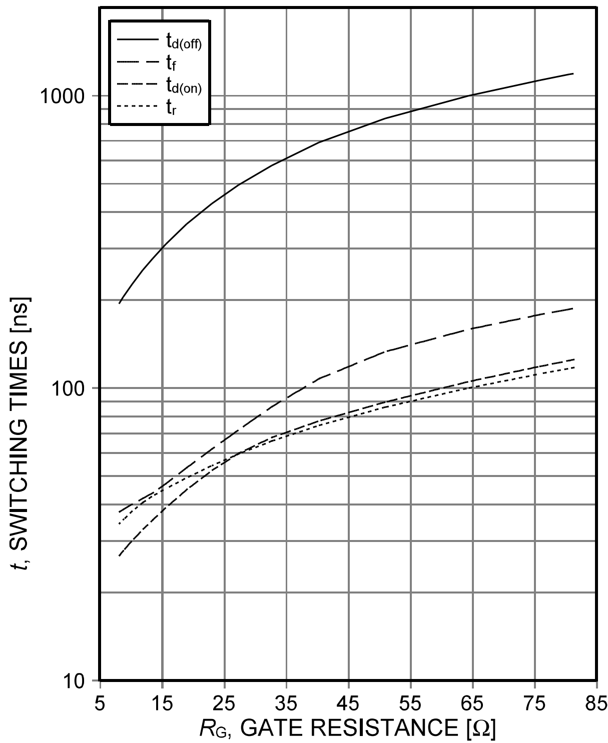


Figure 9. **Typical switching times as a function of gate resistance**

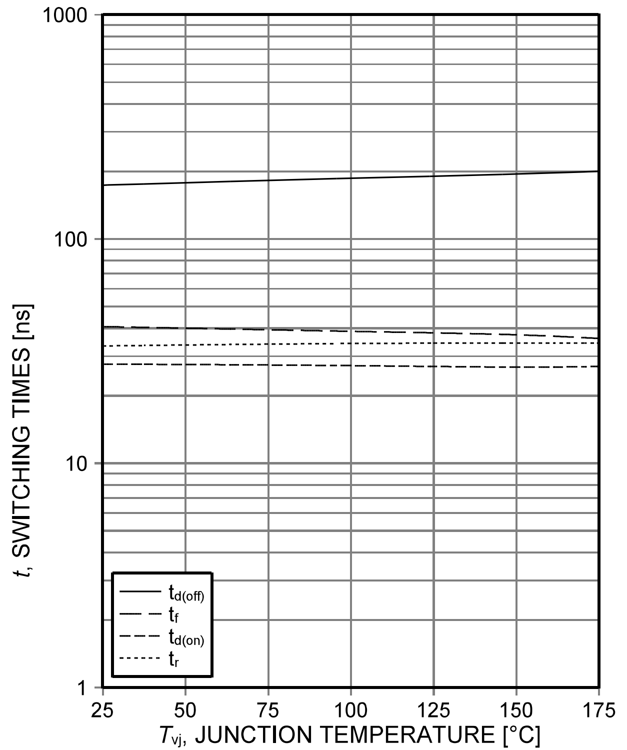
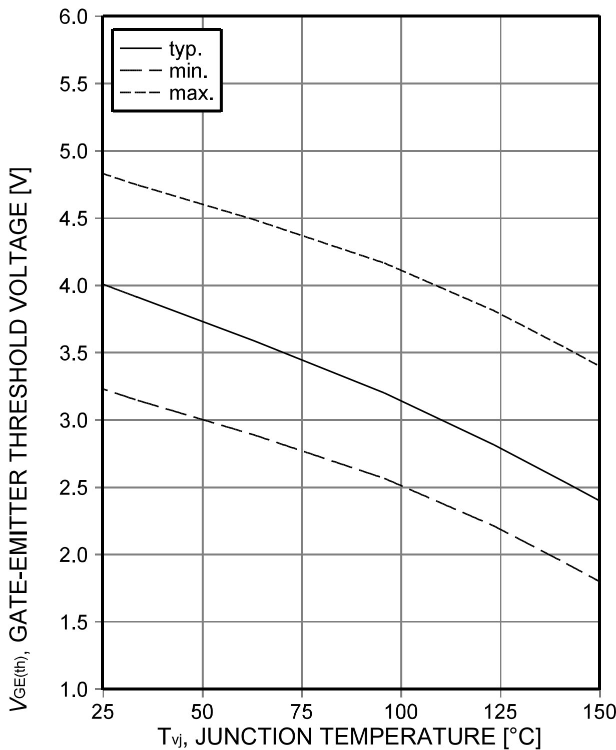


Figure 10. **Typical switching times as a function of junction temperature**



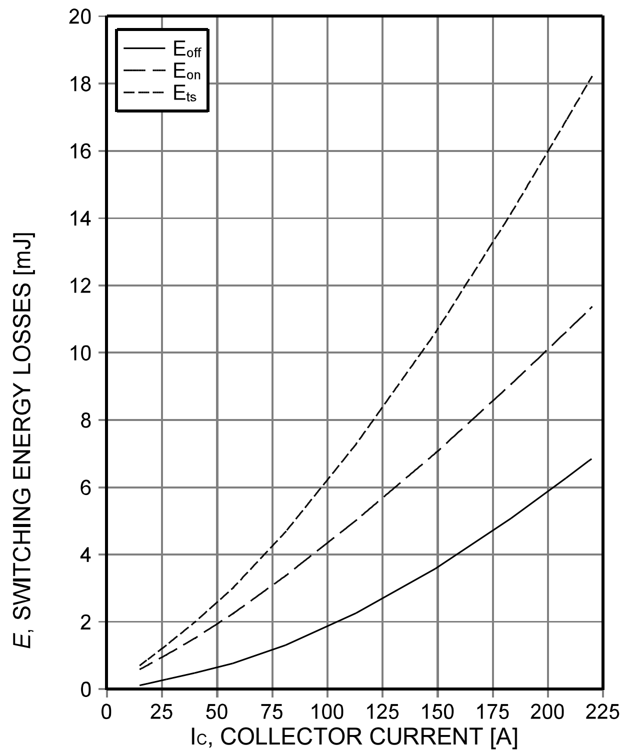


Figure 11.Gate-emitter threshold voltage as a function of junction temperature

Figure 12.Typical switching energy losses as **a** function of collector current

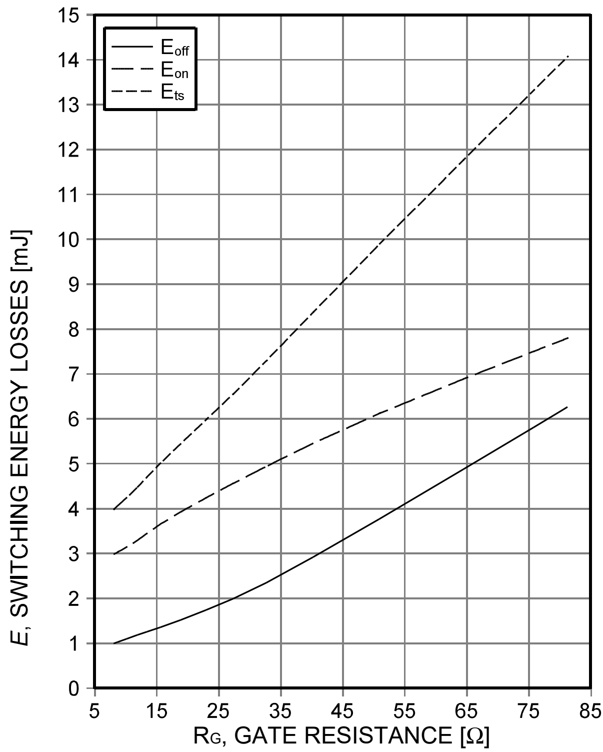


Figure 13.Typical switching energy losses as a function of gate resistance

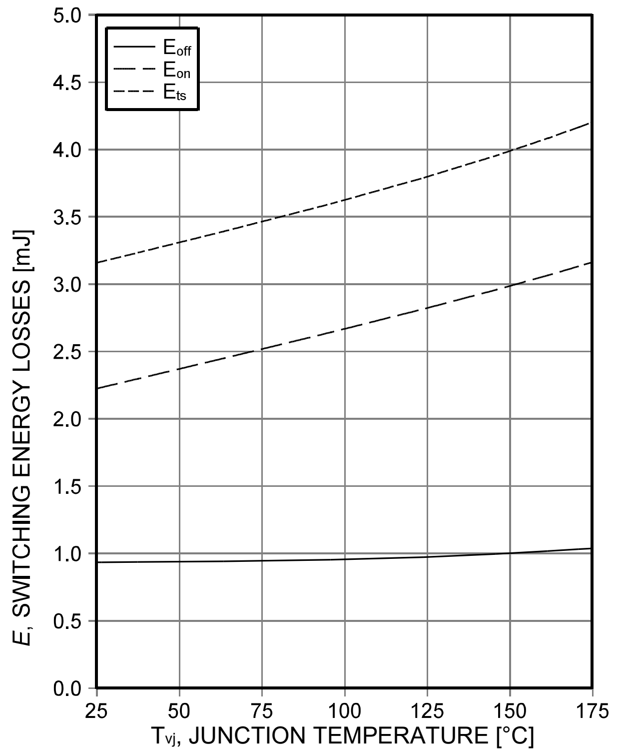


Figure 14.Typical switching energy losses as a function of junction temperature

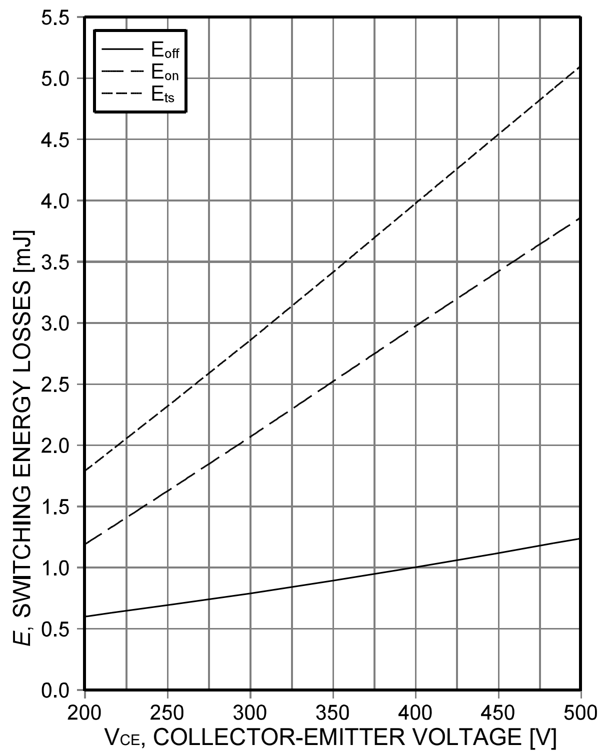


Figure 15.Typical switching energy losses as a function of collector emitter voltage

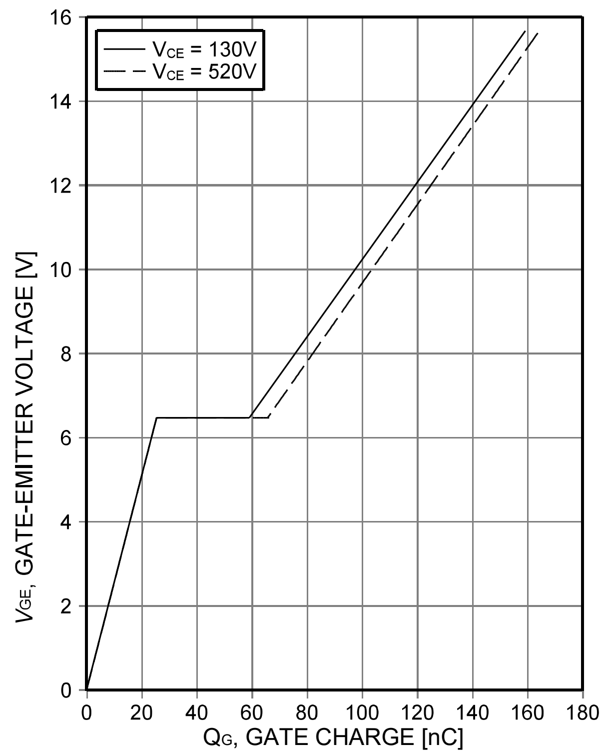
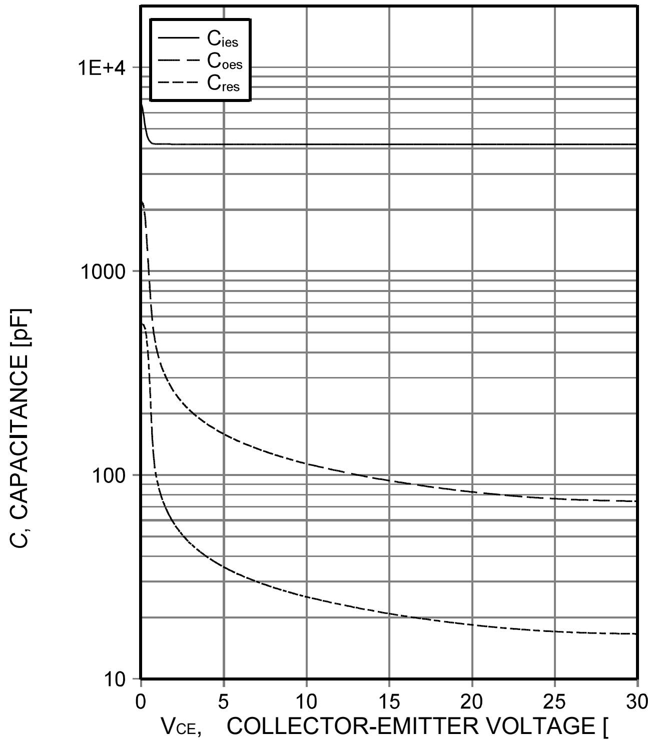


Figure 16.Typical gate charge



V]Figure 17.Typical capacitance as a function of collector-emitter voltage

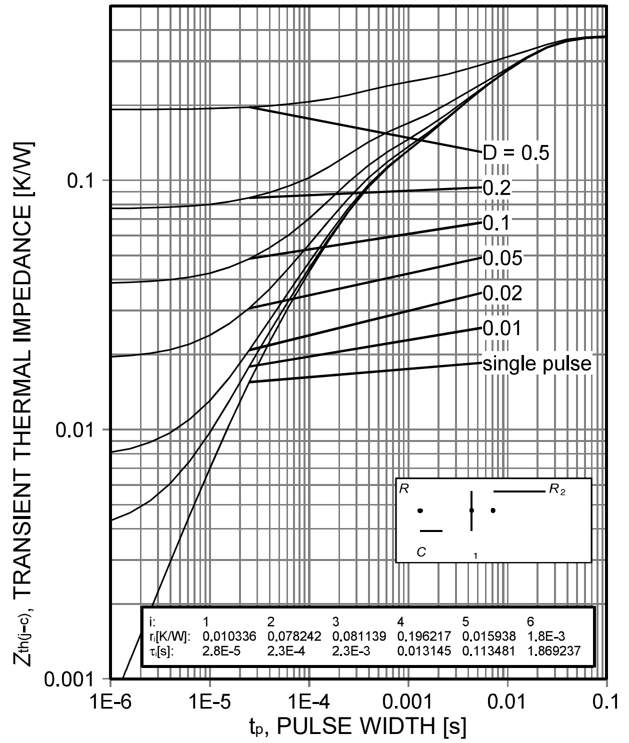


Figure 18.IGBT transient thermal impedance

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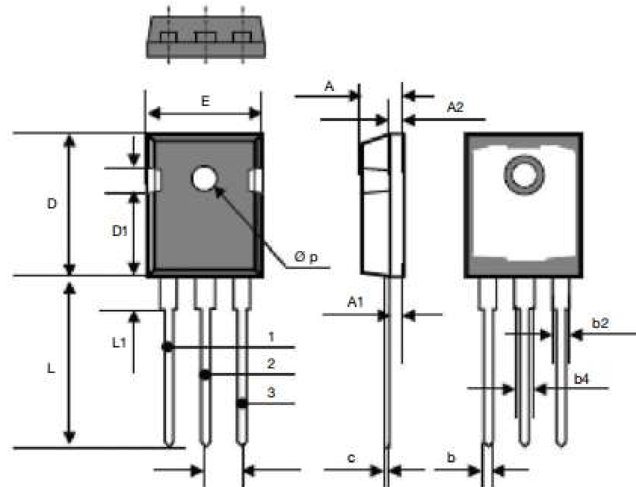

DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.70	5.31	0.185	0.209
A1	2.21	2.59	0.087	0.102
A2	1.50	2.49	0.059	0.098
b	0.99	1.40	0.039	0.055
b2	1.65	2.41	0.065	0.095
b4	2.59	3.43	0.102	0.135
c	0.61 BSC		0.024 BSC	
D	20.80	21.46	0.819	0.845
D1	3.68	5.49	0.145	0.216
(e)	5.46 BSC		0.215 BSC	
E	15.49	16.26	0.610	0.640
L	19.81	20.32	0.780	0.800
L1	4.06	4.50	0.160	0.177
Ø p	3.51	3.66	0.138	0.144